TOSHIBA Photocoupler IRED & Photo IC

# **TLP559**

Digital Logic Ground Isolation Line Receiver Microprocessor System Interfaces Switching Power Supply Feedback Control Transistor Inverter

The TOSHIBA TLP559 consists of a high-output infrared emitting diode and a high speed detector of one chip photo diode-transistor. This unit is 8-lead DIP package.

TLP559 has no internal base connection, and a Faraday shield integrated on the photodetector chip provides an effective common mode noise transient immunity.

So this is suitable for application in noisy environmental condition

- Isolation voltage: 2500 Vrms (min)
- Switching speed:  $t_{pHL} = 0.2\mu s$  (typ.)

$$t_{pLH} = 0.3 \mu s \text{ (typ.) (RL} = 1.9 k\Omega)$$

- TTL compatible
- UL-recognized: UL 1577, File No.E67349.
- cUL-recognized: CSA Component Acceptance Service No.5A File No.E67349.

Unit: mm

9.66±0.25

1.2±0.15

0.25±0.10

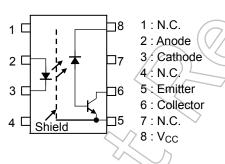
0.25±0.10

0.25±0.10

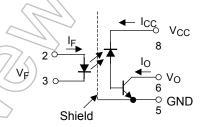
1.1−10C4S

Weight: 0.54 g (typ.)

### Pin Configuration (top view)



### **Schematic**



Start of commercial production 1987-09



#### **Absolute Maximum Ratings (Ta = 25°C)**

	Characteristic		Symbol	Rating	Unit
	Forward current	(Note 1)	lF	25	mA
	Pulse forward current	(Note 2)	IFP	50	mA
LED	Peak transient forward current	(Note 3)	IFPT	1	Α
	Reverse voltage		VR	5	V
	Diode power dissipation	(Note 4)	PD	45	mW
	Output current		lo (	77.8	mA
or	Peak output current		IOP	16	mA
Detector	Output voltage		Yo	−0.5 to 15	V
Ď	Supply voltage		Vcc	-0.5 to 15	V
	Output power dissipation	(Note 5)	PO	100	mW
Ope	rating temperature range		T <sub>opr</sub>	−55 to 100	\ °C \
Stor	age temperature range		Tstg	-55 to 125	ô
Lea	d solder temperature (10 s)	(Note 6)	)) T <sub>sol</sub>	260	Ç
Isola	ation voltage (AC, 60 s, R.H. ≤ 60 %)	(Note 7)	BVs	2500	Vrms

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

- (Note 1) Derate 0.8mA above 70 °C.
- (Note 2) 50 % duty cycle,1 ms pulse width.Derate 1.6 mA / °C above 70 °C.
- (Note 3) Pulse width  $\leq 1 \mu s$ , 300 pps.
- (Note 4) Derate 0.9 mW / °C above 70 °C.
- (Note 5) Derate 2 mW / °C above 70 °C.
- (Note 6) Soldering portion of lead: up to 2 mm from body of the devise.
- (Note 7) Device considered a two-terminal device: Pins 1, 2, 3 and 4 shorted together and pins 5, 6, 7 and 8 shorted together.

#### **Electrical Characteristics (Ta = 25°C)**

	Characteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
	Forward voltage	VF	I <sub>F</sub> = 16 mA	_	1.65	1.85	V
LED	Forward voltage temperature coefficient	ΔV <sub>F</sub> / ΔTa	IF = 16 mA	_	-2	1	mV / °C
	Reverse current	I <sub>R</sub>	V <sub>R</sub> = 5 V		_	10	μΑ
	Capacitance between terminal	Ст	V <sub>F</sub> = 0 V, f = 1 MHz		45	-	pF
Detector	High level output current	IOH (1)	IF = 0 mA, V <sub>CC</sub> = V <sub>O</sub> = 5.5 V		3	500	nA
		IOH (2)	I <sub>F</sub> = 0 mA, V <sub>CC</sub> = V <sub>O</sub> = 15 V	/ <del>\</del>	_	5	
		Іон	I <sub>F</sub> = 0 mA, V <sub>CC</sub> = 15 V V <sub>O</sub> = 15 V, Ta = 70 °C	2	_	50	μА
	High level supply voltage	Іссн	IF = 0 mA, V <sub>CC</sub> = 15 V	_	0.01	1	μΑ
	Supply voltage	Vcc	ICC = 0.01 mA	15		_	V
	Output voltage	Vo	I <sub>O</sub> = 0.5 mA	15	46	$\rightarrow$	V

# **Coupled Electrical Characteristics (Ta = 25°C)**

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
		I <sub>F</sub> = 16 mA, V <sub>CC</sub> = 4.5 V, V <sub>O</sub> = 0.4 V	20	40	1	0,
Current transfer ratio	IO/IF	$I_F = 16 \text{ mA}, V_{CC} = 4.5 \text{ V},$ $V_O = 0.4 \text{ V}, Ta = 0 \text{ to } 70 \text{ °C}$	15	1		%
Low level output voltage	V <sub>OL</sub>	$I_F = 16 \text{ mA}, V_{CC} = 4.5 \text{ V}, I_O = 2.4 \text{ mA}$	_	_	0.4	V

# Isolation Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Capacitance (input-output) (Note 7	)//Cs	$V_S = 0 V, f = 1 MHz$	_	8.0	_	pF
Resistance (input-output) (Note	7) Rs	R.H. ≤ 60 %, Vs = 500 V <sub>DC</sub>	5 × 10 <sup>10</sup>	10 <sup>14</sup>	ı	Ω
Isolation voltage (Note 7	) BVs	AC, 60 s	2500		1	V <sub>rms</sub>

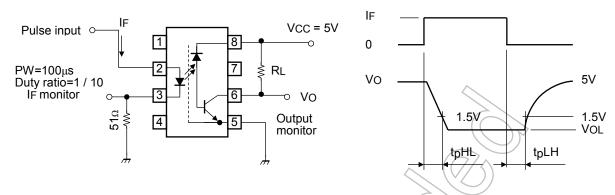
# Switching Characteristics (Ta = 25°C, Vcc = 5V)

Characteristic	Symbol	Test Circuit	Test Condition	Min	Тур.	Max	Unit
Propagation delay time $(H \! \to \! L)$	tрнL	1	IF = 16 mA, R <sub>L</sub> = 1.9 kΩ	ı	0.2	0.8	μS
Propagation delay time $(L\!\!\to\!H)$	t <sub>pLH</sub>	ı	1F - 10 111A, INC - 1.9 N22	ı	0.3	0.8	μS
Common mode transient immunity at logic high output (Note 8)	СМн	2	$I_F$ = 0 mA, $V_{CM}$ = 400 $V_{p-p}$ $R_L$ = 4.1 kΩ	2000	10000	_	V / μs
Common mode transient immunity at logic high output (Note 8)	CML	2	$I_F$ =16 mA, $V_{CM}$ = 400 $V_{p-p}$ RL = 4.1k $\Omega$	-2000	-10000	_	V / μs

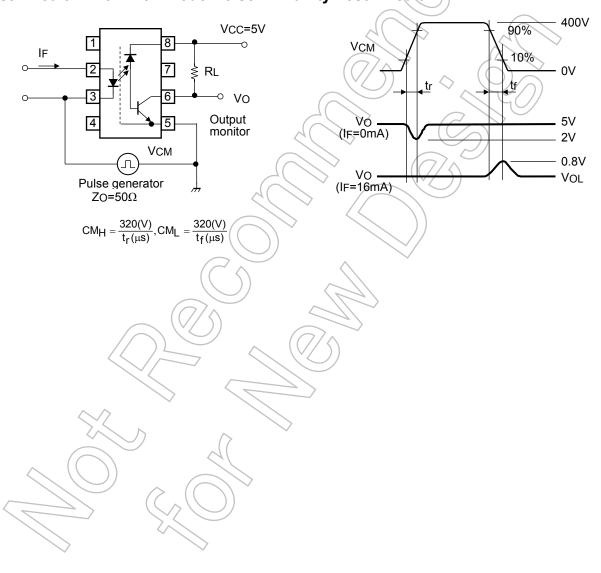
(Note 8) CML is the maximum rate of fall of the common mode voltage that can be sustained with the output voltage in the logic low state (VO < 0.8 V).

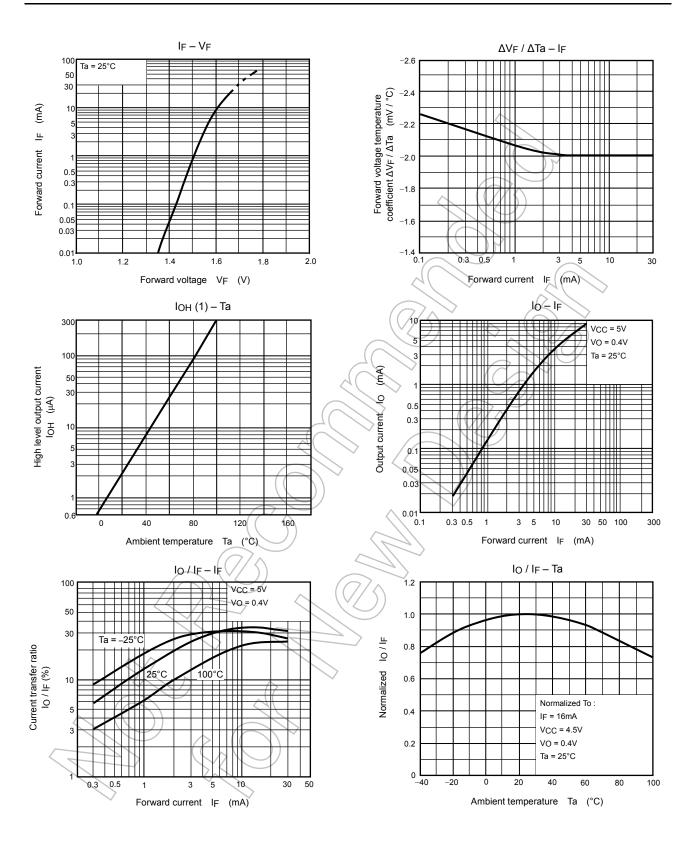
CMH is the maximum rate of rise of the common mode voltage that can be sustained with the output voltage in the logic high state (VO > 2.0 V).

### **Test Circuit 1: Switching Time Test Circuit**

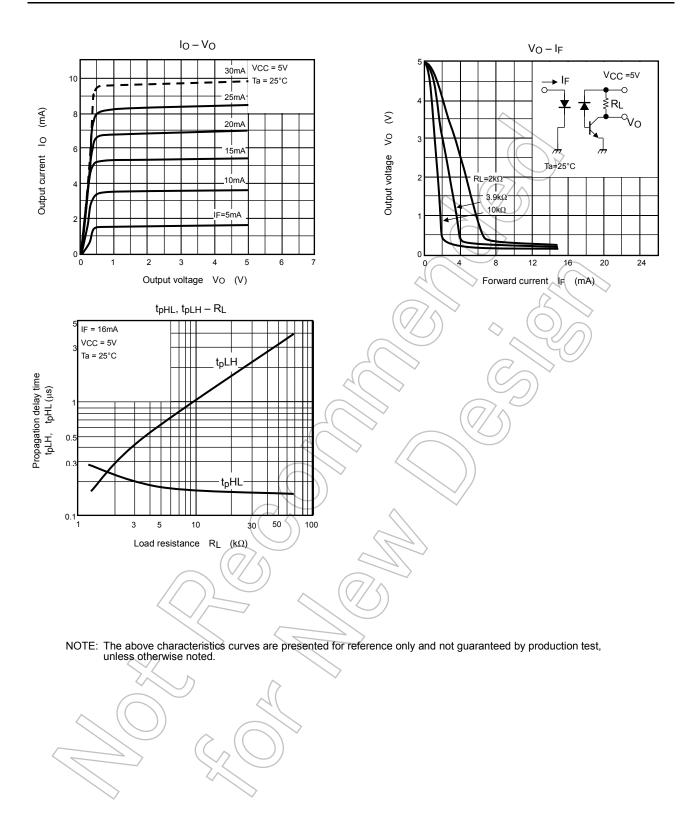


### **Test Circuit 2: Common Mode Noise Immunity Test Circuit**





NOTE: The above characteristics curves are presented for reference only and not guaranteed by production test, unless otherwise noted.



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